CLAIMS

1. A probe pin, comprising:

a coil spring;

a first plunger made from an electrically conductive material, the first plunger including

a first major portion,

a first elastic extension, ~~and~~

a second elastic extension,

the first elastic extension and the second elastic extension~~s~~ extending from the first major portion in parallel in a~~the~~ longitudinal~~same~~ direction of the first plunger,

the first elastic extension and the second elastic extension having different lengths in the longitudinal direction,

the first elastic extension and the second elastic extension having respective first and second inner surfaces opposing to each other,

the first inner surface of the first elastic extension having a first contact portion and the second inner surface of the second elastic extension having a guide projection projecting toward the first elastic extension,

the first contact and the guide projection being spaced away from each other in the longitudinal direction; ~~and~~

a second plunger made from an electrically conductive material, the second plunger including

a second major portion,

a second contact portion provided adjacent the second major portion, and

a guide slot provided away from the second major portion than the second contact portion~~forcedly inserted between the first and the second elastic extensions~~,

~~wherein the first and the second plungers have electric conductivity, and~~

wherein the first and ~~the~~ second plungers are inserted in an inside of the coil spring from one end and the other end~~s~~ of the coil spring, respectively, where~~so that the first and the second elastic extensions of~~ the first and~~plunger hold the~~ second plunger~~s~~ are combined with each other with the guide projection engaged in the guide slot and with the first contact portion~~elastic extension making a~~ forced in contact with ~~a surface of~~ the second contact portion~~plunger~~, allowing the first plunger to slidingly move relative to the second plunger in the longitudinal direction while maintaining~~form thereat~~ an electrical contact~~connection~~ between the first and second contact portions of the first and ~~the~~ second plungers.

~~2. The probe pin according to claim 1,~~

~~wherein at least the first elastic extension has a contact part projected therefrom to form the forced contact with the one surface of the second plunger for making the electric connection between the first and the second plungers.~~

~~3. The probe pin according to claim 1 or 2,~~

~~wherein the first and the second elastic extensions of the first plunger have different lengths from each other.~~

~~4. The probe pin according to any one of claims 1 to 3,~~

~~wherein at least one of the first and the second elastic extensions of the first plunger includes a guide~~

~~projection, and~~

~~wherein the second plunger includes a guide slot in which the guide projection is fitted in so that the first and the second plungers slidingly move relative to each other along the guide slot.~~

2~~5~~. The probe pin ~~according to any one~~ of claim~~s~~ 1~~ to 4~~, wherein

~~wherein~~ the first plunger has a first ~~supporting~~ projection~~s~~ provided at adjacent proximal end~~sportions~~ of the first and ~~the~~ second elastic extensions and a first protrusion~~dropout preventing projections~~ provided distally~~at positions spaced a distance~~ away from the first ~~supporting~~ projection~~s~~;~~, and~~

~~wherein~~ the second plunger has a second ~~supporting~~ projection~~s~~ provided at adjacent a proximal end~~on surfaces thereof opposing in a transverse direction~~ of the second major portion~~plunger~~ and a second protrusion~~dropout preventing projections~~ provided distally~~at positions spaced a distance~~ away from the second ~~supporting~~ projection~~s~~;~~,~~

wherein the~~so that~~ one end of the coil spring is engaged on a portion of the first plunger~~positioned~~ between the first ~~supporting~~ projection~~s~~ and the first protrusion~~dropout preventing projections~~, and the other end of the coil spring is engaged on a portion of the second plunger~~positioned~~ between the second ~~supporting~~ projection~~s~~ and the second protrusion~~dropout preventing projections~~.

3~~6~~. An electronic~~electrical~~ device comprising the~~a~~ probe pin ~~claimed in any~~ of claim~~s~~ 1 or 2~~–5~~.

4. A plunger for use as the first plunger of the probe pin in claim 1 or 2.

5. A plunger for use as the second plunger of the probe pin in claim 1 or 2.